

## Zinc Selenide Stabilized in a Quadrilateral Network Characterized with Optical Emissions

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### Supplementary Data

**Figure S1** The (*hk0*) reflections for (a) the crystal **1·T** prepared by quenching at 630 °C and (b) the crystal **1** prepared by slow cooling to 400 °C.

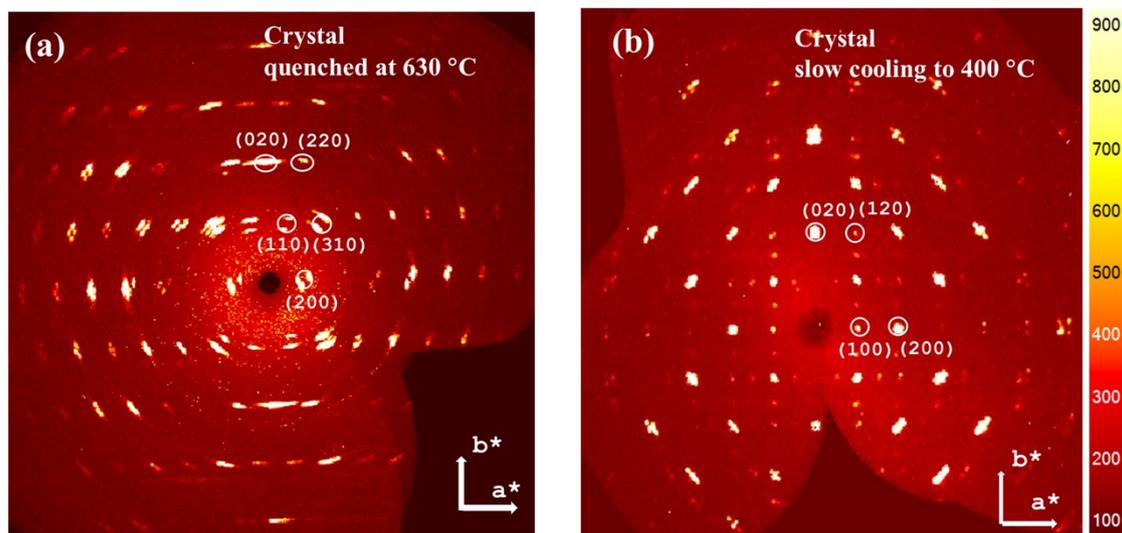
**Figure S2** SEM images and EDS spectrum of single crystals for (a)  $\text{K}_2\text{Zn}_{3.03(5)}\text{Se}_4$  (**1**) and (b)  $\text{K}_2\text{Zn}_{2.56(2)}\text{Mg}_{0.46(5)}\text{Se}_4$  (**2**).

**Figure S3** Observed (black) and calculated (red) powder X-ray diffraction (PXRD) profiles along with the difference plots [*I*<sub>obs</sub>-*I*<sub>calc</sub>] (blue) of the Rietveld refinements for (a)  $\text{K}_2\text{Zn}_3\text{Se}_4$  (**1**) with converged *Rwp* = 9.59% and GOF = 4.96, and (b)  $\text{K}_2\text{Mg}_{0.5}\text{Zn}_{2.5}\text{Se}_4$  (**2**) with converged *Rwp* = 9.98% and GOF = 3.84.

**Figure S4** Differential thermal analysis of the powder samples in two cyclic runs for (a) **1** and (b) **2**.

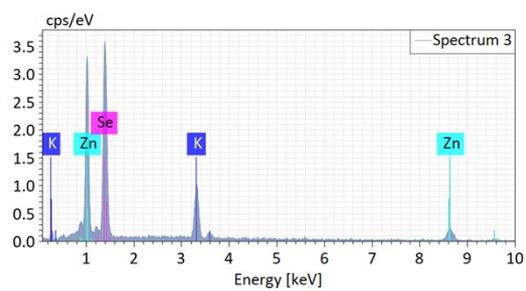
**Figure S5** The UV-vis-NIR reflectance spectrum of (a) **1** and (b) **2**.

**Figure S1** The  $(hk0)$  reflections for (a) the crystal **1·T** prepared by quenching at 630 °C and (b) the crystal **1** prepared by slow cooling to 400 °C.

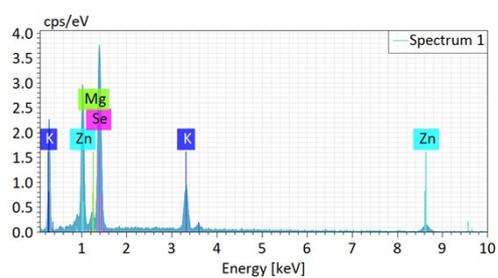
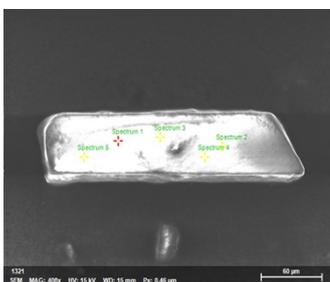


**Figure S2** SEM images and EDS spectrum of single crystals for (a)  $\text{K}_2\text{Zn}_3\text{Se}_4$  (1) and (b)  $\text{K}_2\text{Mg}_{0.5}\text{Zn}_{2.5}\text{Se}_4$  (2).

(a)

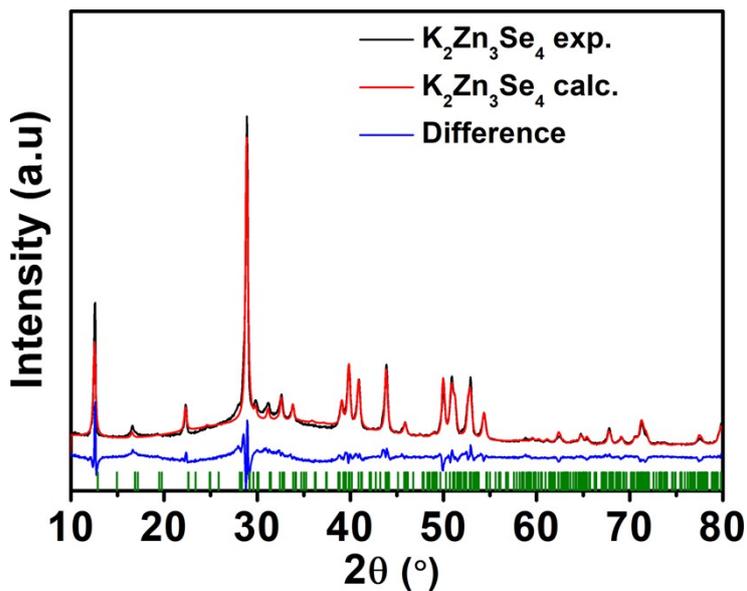


(b)

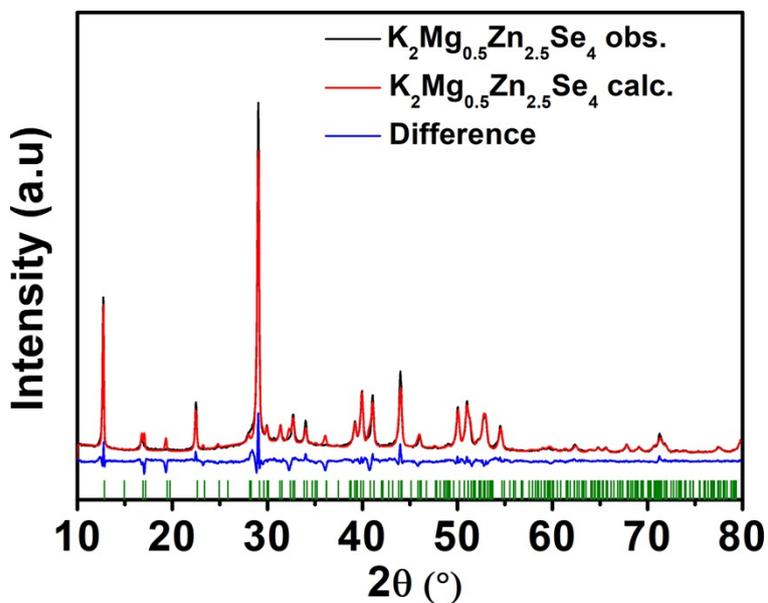


**Figure S3** Observed (black) and calculated (red) powder X-ray diffraction (PXRD) profiles along with the difference plots [I<sub>obs</sub>-I<sub>calc</sub>] (blue) of the Rietveld refinements for (a)  $K_2Zn_{3(5)}Se_4$  (**1**) with converged  $R_{wp} = 9.59\%$  and  $GOF = 4.96$ , and (b)  $K_2Mg_{0.5}Zn_{2.5}Se_4$  (**2**) with converged  $R_{wp} = 9.98\%$  and  $GOF = 3.84$ .

(a)



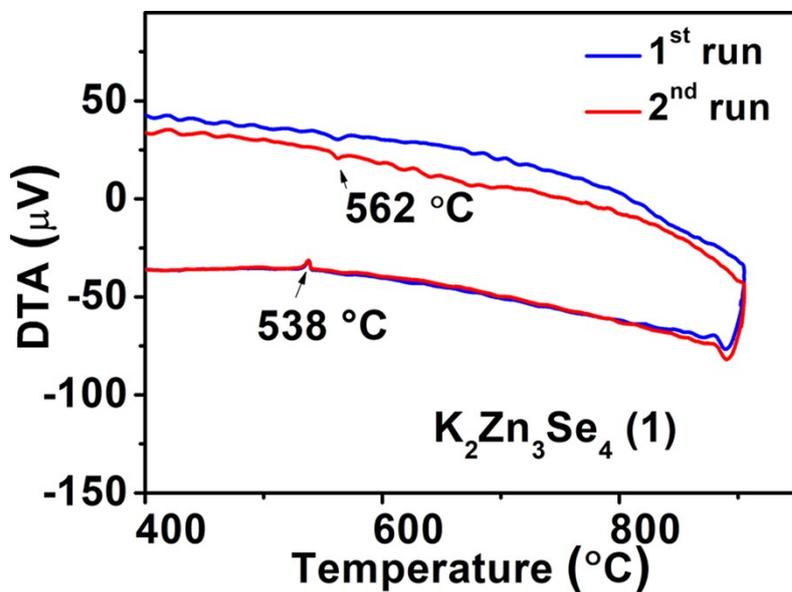
(b)



**Figure S4** Differential thermal analysis of the powder samples in two cyclic runs for

(a) 1 and (b) 2.

(a)



(b)

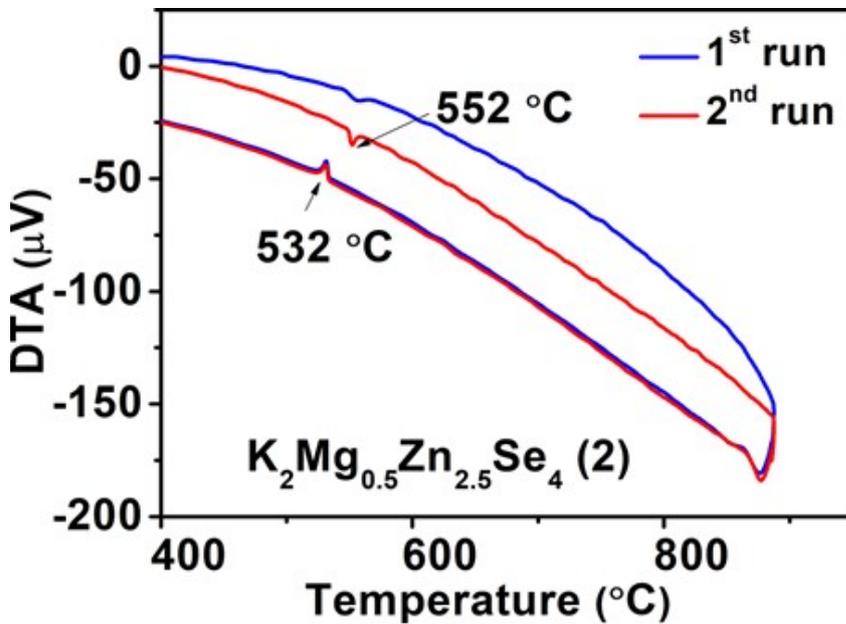
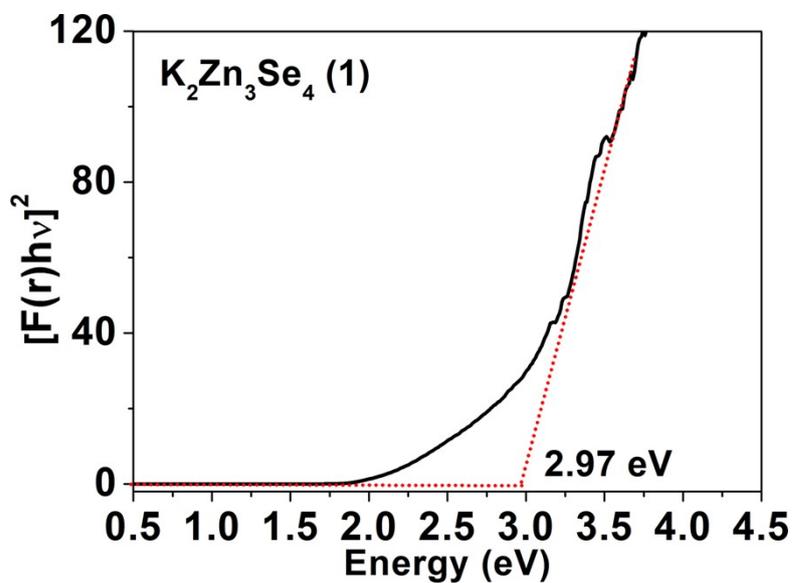


Figure S5 The UV-vis-NIR reflectance spectrum of (a) **1** and (b) **2**.

(a)



(b)

